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October 2016

# FDPC3D5N025X9D

# PowerTrench® Power Clip 25V Symmetric Dual N-Channel MOSFET

#### **Features**

Q1: N-Channel

- Max  $r_{DS(on)}$  = 3.01 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 18 A
- Max  $r_{DS(on)}$  = 3.67 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 16 A

Q2: N-Channel

- Max  $r_{DS(on)}$  = 3.01 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 18 A
- Max  $r_{DS(on)}$  = 3.67 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 16 A
- Low Inductance Packaging Shortens Rise/Fall Times, Resulting in Lower Switching Losses
- MOSFET Integration Enables Optimum Layout for Lower Circuit Inductance and Reduced Switch Node Ringing
- RoHS Compliant

#### **General Description**

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q2) and synchronous (Q1) have been designed to provide optimal power efficiency.

#### **Applications**

- Computing
- Communications
- General Purpose Point of Load

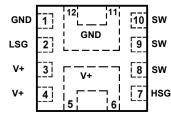


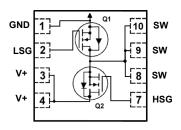


Top



**Bottom** 





Power Clip 33 Symmetric

Pin	Name	Description	Pin	Name	Description	Pin	Name	Description
1,11,12	GND(LSS)	Low Side Source	3,4,5,6	V+(HSD)	High Side Drain	8,9,10	sw	Switching Node, Low Side Drain
2	LSG	Low Side Gate	7	HSG	High Side Gate			

#### **MOSFET Maximum Ratings** T<sub>A</sub> = 25 °C unless otherwise noted.

Symbol	Param	eter		Q1	Q2	Units
$V_{DS}$	Drain to Source Voltage			25	25	V
$V_{GS}$	Gate to Source Voltage			±12	±12	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C	<sub>C</sub> = 25 °C (Note5)		74	
	-Continuous	T <sub>C</sub> = 100 °C	(Note5)	47	47	Α
ID	-Continuous	T <sub>A</sub> = 25 °C		18 <sup>Note1a</sup>	18 <sup>Note1b</sup>	A
	-Pulsed	T <sub>A</sub> = 25 °C	(Note 4)	349	349	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	96	96	mJ
П	Power Dissipation for Single Operation	T <sub>C</sub> = 25 °C		26	26	W
$P_{D}$	Power Dissipation for Single Operation	T <sub>A</sub> = 25 °C		1.8 <sup>Note1a</sup>	1.8 <sup>Note1b</sup>	VV
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperation	ature Range		-55 to	+150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.8	4.8	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	70 <sup>Note1a</sup>	70 <sup>Note1b</sup>	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	135 <sup>Note1c</sup>	135 <sup>Note1d</sup>	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDPCN025X9D	FDPC3D5N025X9D	Power Clip 33 Symm	13 "	12 mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted.

Symbol	Parameter	Test Conditions	Type	Min.	Тур.	Max.	Units
Off Chara	acteristics						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	Q1	25			V
DVDSS	Dialii to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q2	25			V
$\Delta BV_{DSS}$	Breakdown Voltage Temperature	I <sub>D</sub> = 250 μA, referenced to 25 °C	Q1		23		mV/°C
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C	Q2		23		IIIV/ C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V	Q1			1	μΑ
I <sub>DSS</sub>		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$	Q2			1	μΑ
	Gate to Source Leakage Current,	V <sub>GS</sub> = 12 V/-8 V, V <sub>DS</sub> = 0 V	Q1			±100	nA
I <sub>GSS</sub>	Forward	V <sub>GS</sub> = 12 V/-8 V, V <sub>DS</sub> = 0 V	Q2			±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, \ I_{D} = 250 \ \mu A$ $V_{GS} = V_{DS}, \ I_{D} = 250 \ \mu A$	Q1 Q2	1.0 1.0	1.5 1.5	3.0 3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 μA, referenced to 25 °C $I_D$ = 250 μA, referenced to 25 °C	Q1 Q2		-4 -4		mV/°C
	Drain to Source On Resistance	$V_{GS} = 10V, I_D = 18 A$ $V_{GS} = 4.5 V, I_D = 16 A$ $V_{GS} = 10 V, I_D = 18 A, T_J = 125 °C$	Q1		2.0 2.4 2.87	3.01 3.67 4.32	mO
r <sub>DS(on)</sub>	Dialit to Source Off Resistance	$V_{GS}$ = 10V, $I_D$ = 18 A $V_{GS}$ = 4.5 V, $I_D$ = 16 A $V_{GS}$ = 10 V, $I_D$ = 18 A , $T_J$ =125 °C	Q2		2.5 2.9 3.6	3.01 3.67 4.33	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 18 A V <sub>DS</sub> = 5 V, I <sub>D</sub> = 18 A	Q1 Q2		133 124		S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	Q1:	Q1 Q2		2385 2385	3340 3340	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$ $Q2:$	Q1 Q2		612 612	860 860	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2		78 78	130 130	pF
R <sub>g</sub>	Gate Resistance		Q1 Q2	0.1 0.1	0.6 0.6	1.8 1.8	Ω

### **Switching Characteristics**

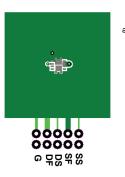
t <sub>d(on)</sub>	Turn-On Delay Time			Q1 Q2	10 10	20 20	ns
t <sub>r</sub>	Rise Time	Q1: V <sub>DD</sub> = 13V, I <sub>D</sub> = 18	$V_{DD}$ = 13V, $I_{D}$ = 18 A, $R_{GEN}$ = 6 $\Omega$		3	10 10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	Q2:			29 29	46 46	ns
t <sub>f</sub>	Fall Time	VDD - 13 V, ID - 10			3	10 10	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	Q1	Q1 Q2	36 36	51 51	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 4.5 V		Q1 Q2	17 17	24 24	nC
Q <sub>gs</sub>	Gate to Source Gate Charge		Q2 V <sub>DD</sub> = 13 V, I <sub>D</sub>	Q1 Q2	5.3 5.3		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		= 18 A	Q1 Q2	3.9 3.9		nC

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted.

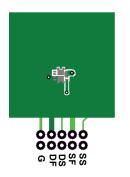
Symbol	Parameter	Test Conditions	Type	Min.	Тур.	Max.	Units
Drain-Sou	rce Diode Characteristics						
$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 18 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 18 \text{ A}$ (Note 2)	Q1 Q2		0.8 0.8	1.2 1.2	٧
I <sub>S</sub>	Diode continuous forward current	T <sub>C</sub> = 25 °C	Q1 Q2		74 74		Α
I <sub>S,Pulse</sub>	Diode pulse current	1c-25 C	Q1 Q2		349 349		Α
t <sub>rr</sub>	Reverse Recovery Time	Q1 I <sub>F</sub> = 18 A, di/dt = 100 A/μs	Q1 Q2		35 35	56 56	ns
Q <sub>rr</sub>	Reverse Recovery Charge	Q2 $I_F = 18 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$	Q1 Q2		19 19	35 35	nC

#### Notes:

 $1.R_{\theta,JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta,CA}$  is determined by the user's board design.



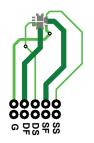
a. 70 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b. 70 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



c. 135 °C/W when mounted on a minimum pad of 2 oz copper



d. 135 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu s,$  Duty cycle < 2.0%.
- 3. Q1 :E<sub>AS</sub> of 96 mJ is based on starting  $T_J = 25$  °C; N-ch: L = 3 mH, I<sub>AS</sub> = 8 A, V<sub>DD</sub> = 25 V, V<sub>GS</sub> = 10 V. 100% test at L= 0.1 mH, I<sub>AS</sub> = 26 A. Q2: E<sub>AS</sub> of 96 mJ is based on starting  $T_J = 25$  °C; N-ch: L = 3 mH, I<sub>AS</sub> = 8 A, V<sub>DD</sub> = 25 V, V<sub>GS</sub> = 10 V. 100% test at L= 0.1 mH, I<sub>AS</sub> = 26 A.
- 4. Pulse Id refers to Figure.11 & Figure. 26 Forward Bias Safe Operation Area.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

# Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted.

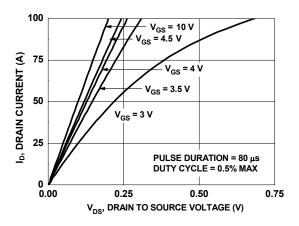


Figure 1. On Region Characteristics

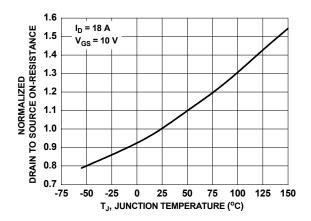


Figure 3. Normalized On Resistance vs. Junction Temperature

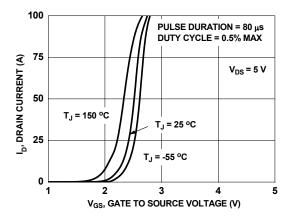


Figure 5. Transfer Characteristics

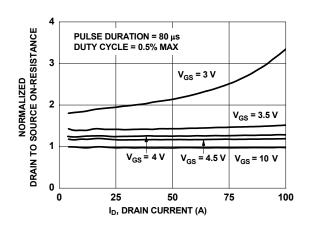


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

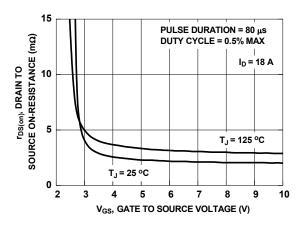


Figure 4. On-Resistance vs. Gate to Source Voltage

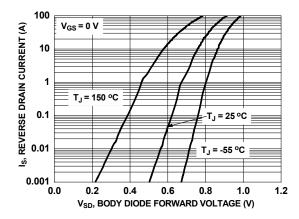


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

# Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted.

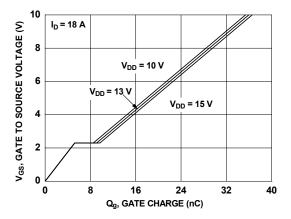


Figure 7. Gate Charge Characteristics

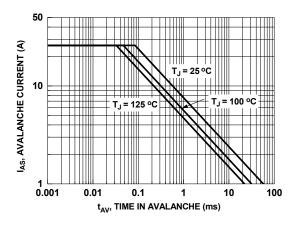


Figure 9. Unclamped Inductive Switching Capability

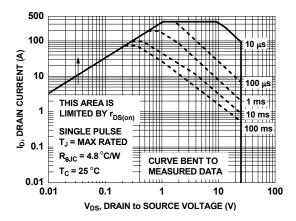


Figure 11. Forward Bias Safe Operating Area

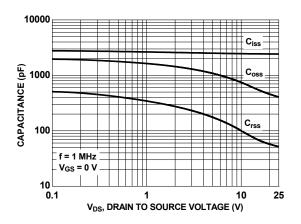


Figure 8. Capacitance vs. Drain to Source Voltage

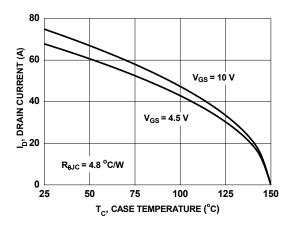


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

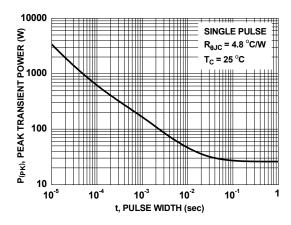


Figure 12. Single Pulse Maximum Power Dissipation

#### Typical Characteristics (Q1 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted.

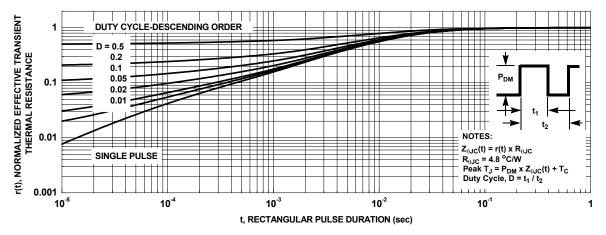


Figure 13. Junction-to-Case Transient Thermal Response Curve

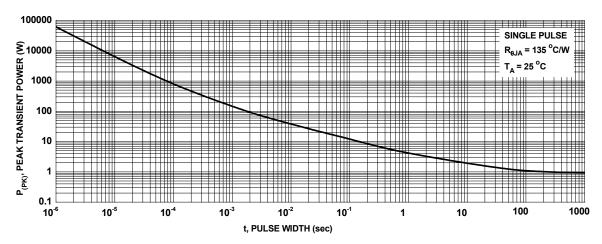


Figure 14. Single Pulse Maximum Power Dissipation

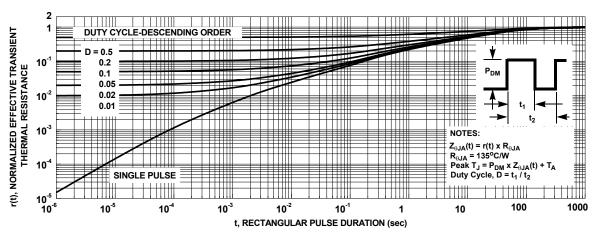


Figure 15. Junction-to-Ambient Transient Thermal Response Curve

#### Typical Characteristics (Q2 N-Channel) T<sub>J</sub> = 25 °C unless otherwise noted.

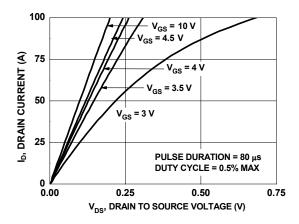


Figure 16. On-Region Characteristics

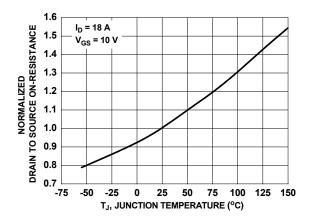


Figure 18. Normalized On-Resistance vs. Junction Temperature

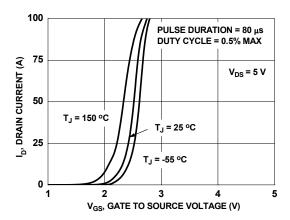


Figure 20. Transfer Characteristics

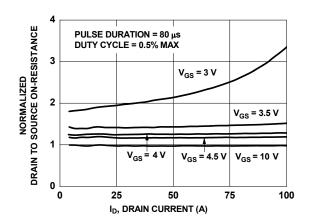


Figure 17. Normalized on-Resistance vs. Drain **Current and Gate Voltage** 

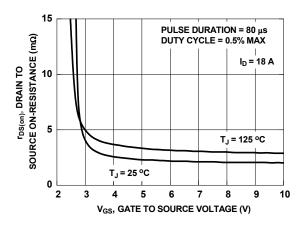


Figure 19. On-Resistance vs. Gate to **Source Voltage** 

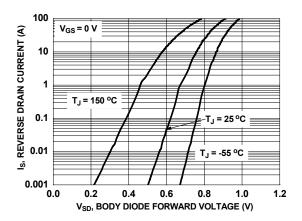


Figure 21. Source to Drain Diode Forward Voltage vs. Source Current

## Typical Characteristics (Q2 N-Channel) T<sub>J</sub> = 25°C unless otherwise noted.

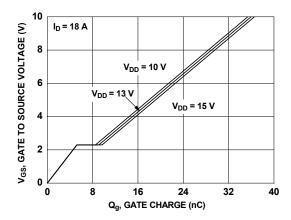


Figure 22. Gate Charge Characteristics

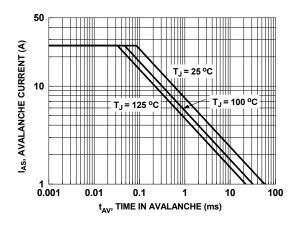


Figure 24. Unclamped Inductive Switching Capability

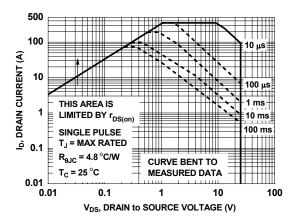


Figure 26. Forward Bias Safe Operating Area

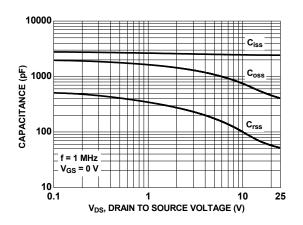


Figure 23. Capacitance vs. Drain to Source Voltage

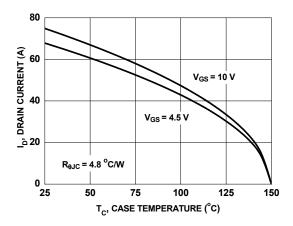


Figure 25. Maximum Continuous Drain Current vs. Case Temperature

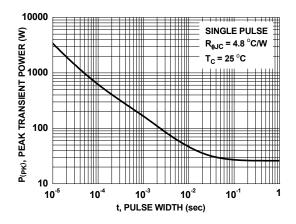


Figure 27. Single Pulse Maximum Power Dissipation

# Typical Characteristics (Q2 N-Channel) T<sub>J</sub> = 25 °C unless otherwise noted.

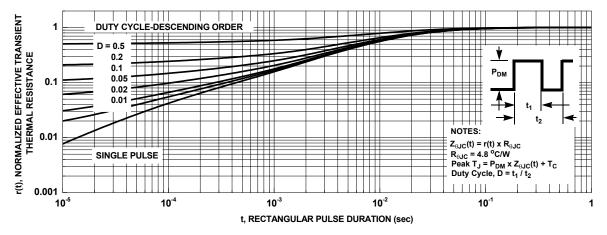


Figure 28. Junction-to-Case Transient Thermal Response Curve

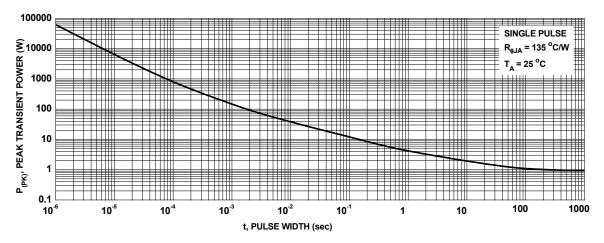


Figure 29. Single Pulse Maximum Power Dissipation

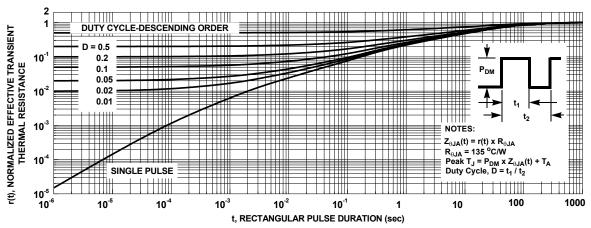
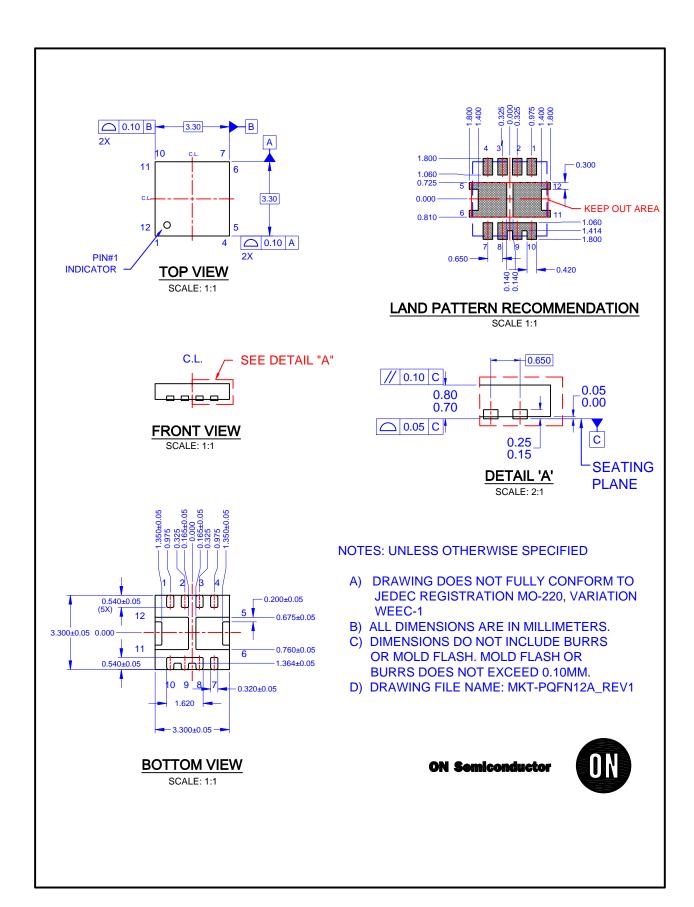


Figure 30. Junction-to-Ambient Transient Thermal Response Curve



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